

Notice of References Cited

Application/Control No.

10/537,194

Applicant(s)/Patent Under
Reexamination
TAKASHIMA ET AL.

Examiner

John P. Sheehan

Art Unit

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,062,905	11-1991	Tomita et al.	148/111
*	B US-5,037,493	08-1991	Tomita et al.	148/111
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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N	WO 2007/074987 A1	05-2007	PCT	Bae et al.	-----
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R					
S					
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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